

“Artifact Reduction Based on Sinogram Interpolation for the 3D Reconstruction of Nanoparticles Using Electron Tomography”. Sentosun K, Lobato I, Bladt E, Zhang Y, Palenstijn WJ, Batenburg KJ, Van Dyck D, Bals S, Particle and particle systems characterization **34**, 1700287 (2017). <http://doi.org/10.1002/ppsc.201700287>